

## UNITED STATES PATENT AND TRADEMARK OFFICE



UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER FOR PATENTS P.O. Box 1450 Alexandria, Virginia 22313-1450 www.uspto.gov

		•			
APPLICATION	NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/787,07	0	02/25/2004	Andrew B. Kahng	0321.67421	2850
24978	7590	11/02/2005		EXAM	INER
GREE	R, BURNS	& CRAIN	LIN, SUN J		
300 S V	VACKER D	R			
25TH FLOOR				ART UNIT	PAPER NUMBER
CHICAGO, IL 60606				2825	
•				DATE MAILED: 11/02/2005	

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)				
Office Action Commons	10/787,070	KAHNG ET AL.				
Office Action Summary	Examiner	Art Unit				
	Sun J. Lin	2825				
<ul> <li>The MAILING DATE of this communication app</li> <li>Period for Reply</li> </ul>	ears on the cover sheet with the c	orrespondence address				
A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 2 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.  - Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.  - If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.  - Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).						
Status						
Responsive to communication(s) filed on 25 Fe     This action is FINAL. 2b) ☐ This     Since this application is in condition for allowar closed in accordance with the practice under E	action is non-final. nce except for formal matters, pro					
Disposition of Claims						
4) ☐ Claim(s) 1-38 is/are pending in the application. 4a) Of the above claim(s) is/are withdraw 5) ☐ Claim(s) 1-38 is/are allowed. 6) ☐ Claim(s) is/are rejected. 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction and/or	vn from consideration.					
Application Papers						
9) ☐ The specification is objected to by the Examiner 10) ☐ The drawing(s) filed on 7/19/2004 is/are: a) ☐ a Applicant may not request that any objection to the o Replacement drawing sheet(s) including the correcti 11) ☐ The oath or declaration is objected to by the Examiner	accepted or b) $\square$ objected to by the drawing (s) be held in abeyance. See on is required if the drawing (s) is object.	e 37 CFR 1.85(a). ected to. See 37 CFR 1.121(d).				
Priority under 35 U.S.C. § 119						
<ul> <li>12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).</li> <li>a) All b) Some * c) None of:</li> <li>1. Certified copies of the priority documents have been received.</li> <li>2. Certified copies of the priority documents have been received in Application No.</li> <li>3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).</li> <li>* See the attached detailed Office action for a list of the certified copies not received.</li> </ul>						
Attachment(s)	4) 🗖 Intonious Summans	(DTO 412)				
<ol> <li>Notice of References Cited (PTO-892)</li> <li>Notice of Draftsperson's Patent Drawing Review (PTO-948)</li> <li>Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)</li> <li>Paper No(s)/Mail Date <u>08/18/04</u>.</li> </ol>	4) Interview Summary Paper No(s)/Mail Da 5) Notice of Informal P 6) Other:					

Application/Control Number: 10/787,070

Art Unit: 2825

# DETAILED ACTION

Page 2

1. This office action is in response to application 10/787,070 filed on 02/25/2004. Claims 1 – 38 remain pending in the application.

#### **QUAYLE ACTION**

2. This application is in condition for allowance except for the following formal matters:

### **Specification Objections**

Page 5, line 7, change " $\mu_{1+2}+k\sigma_{1+2}$ " to —  $\mu+k\sigma$  —.

Page 17, line 3, change "the design layout" to —a mask design layout—.

Page 17, line 4, before "design" insert —mask—.

Page 17, line 4, change "the determined" to —a determined—.

Page 17, line 6, before "design" insert —mask—.

Page 17, line 6, change "the desired" to —a desired—.

Page 17, line 7, before "total" delete —the—.

Page 17, line 7, before "design" insert —mask—.

Similar informalities listed in "Claim Objections" given below.

## **Drawing Objections**

Fig. 1, between "Box 12 and EXIT" label —YES—.

Fig. 1, between "Box 12 and BOX 14" label —NO—.

Fig. 2 should be labeled as —(PRIOR ART)—.

## Claim Objections

Claim 1, line 3, change "the mask design" to —a mask design—.

Claim 2, line 1, change "said first" to —a first—.

Claim 10, line 3, change " $\mu_{1+2}$ + $k\sigma_{1+2}$ " to —  $\mu$ + $k\sigma$  —.

Claim 10, line 4, delete — where  $\mu$ +k $\sigma$  —.

Claim 10, line 4, change " $\mu$  is the mean" to  $-\mu_i$  is a mean—.

Claim 10, line 4, provide clear definition of k and its range..

Application/Control Number: 10/787,070

Page 3

Art Unit: 2825

```
Claim 10, line 4, change "\sigma is the standard deviation" to — \sigma_i is a standard
deviation—.
Claim 10, line 5, change "\mu+k\sigma" to — \mu_i+k\sigma_i —.
Claim 10, line 5, after "yield" insert —, for all i = 1, 2 —.
Claim 13, line 1, after "is" delete —a—.
Claim 16, line 3 – 4, change "the circuit" to —a circuit—.
Claim 16, line 6, after "cost;" insert —and—.
Claim 16, line 7, after "based" insert —on—.
Claim 16, line 9, change "a minimum" to —said minimum—.
Claim 19, line 2, before "output" insert —the—.
Claim 19, line 4, delete —determined—.
Claim 19, line 7, after "second" delete —first—.
Claim 19, line 9, change "a minimum" to —said minimum—.
Claim 19, line 11, change "a minimum" to —said minimum—.
Claim 21, line 3, change "\mu_{1+2}+k\sigma_{1+2}" to — \mu+k\sigma —.
Claim 21, line 4, delete — where \mu+k\sigma —.
Claim 21, line 4, change "\mu is the mean" to -\mu_i is a mean—.
Claim 21, line 4, provide clear definition of k and its range.
Claim 21, line 4, change "\sigma is the standard deviation" to — \sigma_i is a standard
deviation—.
Claim 21, line 5, change "\mu+k\sigma" to — \mu_i+k \sigma_i —.
Claim 21, line 5, after "yield" insert —, for all i = 1, 2—.
Claim 24, line 1, after "is" delete —a—.
Claim 27, line 6, before "each" delete —said—.
Claim 27, line 10, after "within" insert —a—.
Claim 28, line 1, before "each" delete —said—.
Claim 31, line 2, change "the mask" to —a mask—.
Claim 31, line 4, change "the determined" to —a determined—.
Claim 31, line 5 delete —on the medium—.
Claim 32, line 3, change "\mu_{1+2}+k\sigma_{1+2}" to — \mu+k\sigma —.
```

Claim 32, line 4, delete — where  $\mu$ +k $\sigma$  —.

Claim 32, line 4, change " $\mu$  is the mean" to  $-\mu_i$  is a mean—. Claim 32, line 4, provide clear definition of k and its range.

Application/Control Number: 10/787,070 Page 4

Art Unit: 2825

```
Claim 32, line 4, change "\sigma is the standard deviation" to — \sigma_i is a standard deviation—.
```

Claim 32, line 5, change " $\mu$ +k $\sigma$ " to —  $\mu_i$ +k $\sigma_i$  —.

Claim 32, line 5, after "yield" insert —, for all i = 1, 2—.

Claim 33, line 5, delete —on the medium —.

Claim 34, line 4, change "the circuit" to —a circuit—.

Claim 34, line 6, after "based" insert —on—.

Claim 34, line 6 – 7, change "said" predetermined" to —a predetermined—.

Claim 37, line 3, change " $\mu_{1+2}+k\sigma_{1+2}$ " to —  $\mu+k\sigma$  —.

Claim 37, line 4, delete — where  $\mu$ +k $\sigma$  —.

Claim 37, line 4, change " $\mu$  is the mean" to  $-\mu_i$  is a mean—.

Claim 37, line 4, provide clear definition of k and its range.

Claim 37, line 4, change " $\hat{\sigma}$  is the standard deviation" to —  $\sigma_i$  is a standard deviation—.

Claim 37, line 5, change " $\mu$ +k $\sigma$ " to —  $\mu_i$ +k  $\sigma_i$  —.

Claim 37, line 5, after "yield" insert —, for all i = 1, 2—.

Appropriate corrections are required.

Prosecution on the merits is closed in accordance with the practice under *Ex* parte Quayle, 1935 C.D. 11, 453 O.G. 213.

A shortened statutory period for reply to this action is set to expire **TWO**MONTHS from the mailing date of this letter.

### **Reasons for Allowance**

3. The following is an examiner's statement of reasons for allowance:

Claims 1 – 38 are allowed because the prior art does not teach or fairly suggest the following subject matter:

- A method for performing a mask design layout resolution enhancement comprising <u>determining a first level of correction for a mask design layout for</u> <u>a predetermined parametric yield with a minimum total correction cost</u> in combination with other limitations as recited in independent Claim 1;
- · A method for minimizing a cost of correction of a mask design layout

Application/Control Number: 10/787,070

Art Unit: 2825

comprising a <u>correction?the mask design layout at a first level of correction of based on a correction algorithm if a first probability density function obtained for a signal arrival time at an output of a circuit on the mask layout does not satisfy a predetermined parametric yield with a minimum total correction cost in combination with other limitations as recited in independent Claim 16;</u>

- A method for performing a mask design layout resolution enhancement comprising <u>determining a an edge placement error (EPC) tolerance corresponding to a critical dimension (CD) variation tolerance for each of a plurality of features in the mask design layout and correcting each of the plurality of features so that at least one edge on the each of said plurality of features prints within a tolerance based on said EPE tolerance in combination with other limitations as recited in independent Claim 27;
  </u>
- A machine readable medium for storing <u>a program in a system for performing</u>
   <u>a mask design layout resolution enhancement in which a level of correction</u>
   <u>for a mask design layout for a predetermined parametric yield with a minimum</u>
   <u>total correction cost</u> in combination with other limitations as recited in
   independent Claim 31 and Claim 33, respectively;
- A system for minimizing a cost of correction of a mask design layout comprising a <u>correction means for determining a first level of correction of the</u> <u>mask design layout based on a correction algorithm if a first probability</u> <u>density function obtained by an analyzing means does not satisfy a</u> <u>predetermined parametric yield with a minimum total correction cost</u> in combination with other limitations as recited in independent Claim 34.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance".

#### Conclusion

4. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Sun J Lin whose telephone number is (571) 272 - 1899. The examiner can normally be reached on Monday-Friday 9:30AM - 6:30PM.

Application/Control Number: 10/787,070 Page 6

Art Unit: 2825

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Matthew S Smith can be reached on (571) 272 - 1907. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

James Sun Lin

Sun J. Lin Patent Examiner Art Unit 2825 October 27, 2005

فتوليده